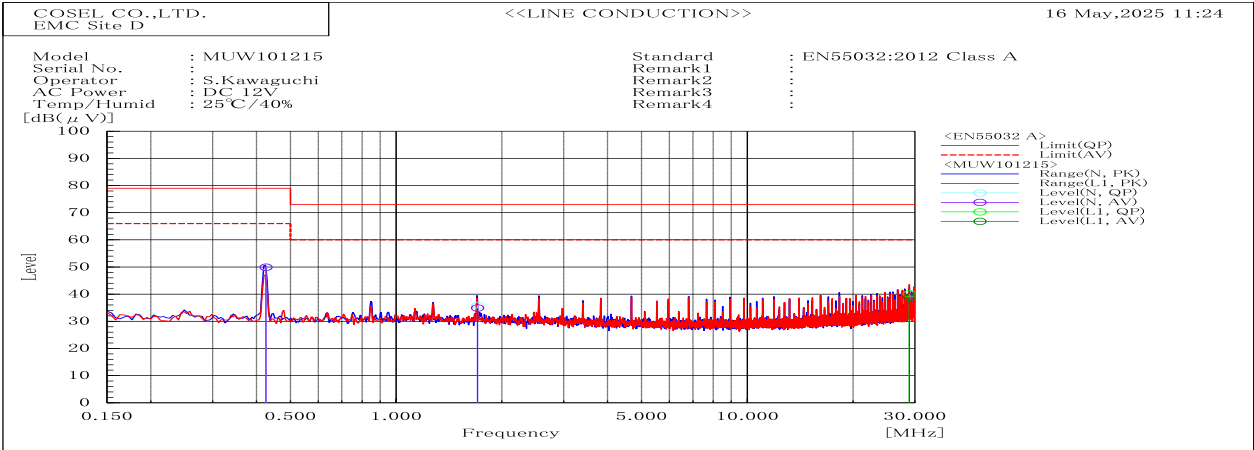
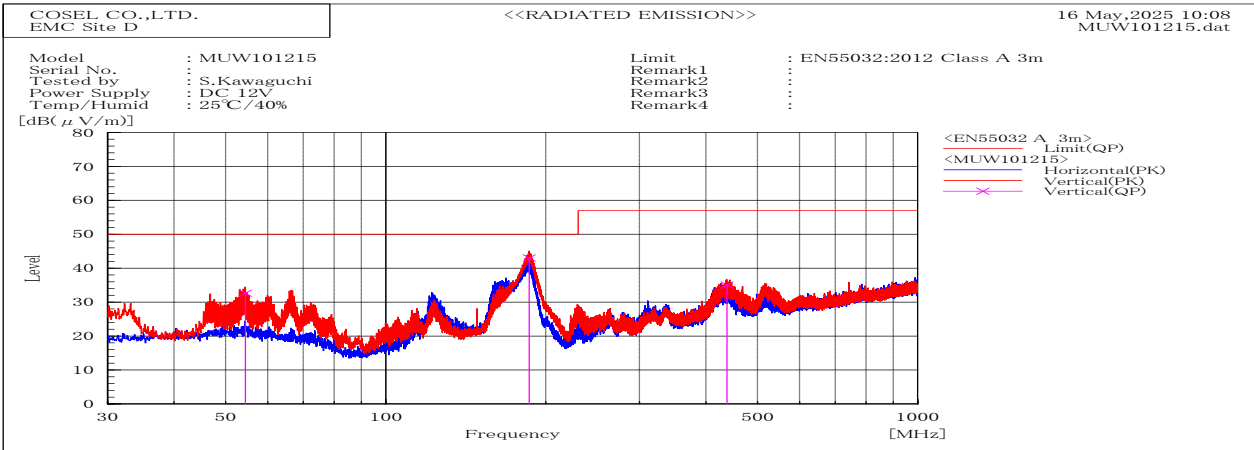


DATA SHEET		Date	16-May-25
Model	MUW101215	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



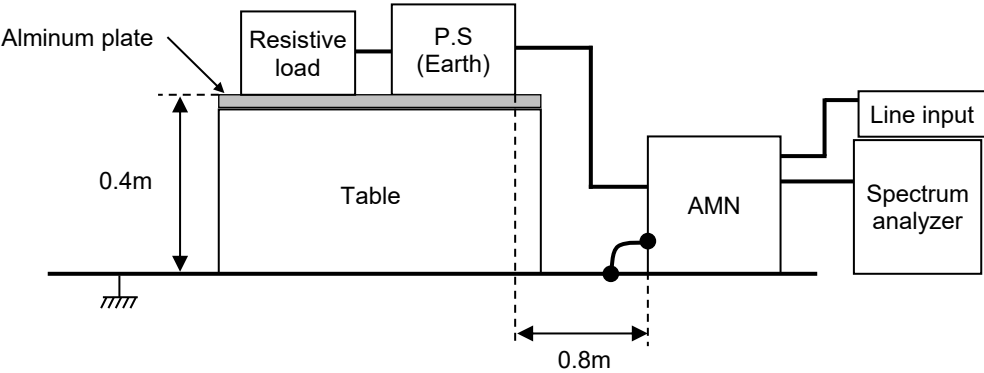
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
28.954	L1	40.2	38.9	73	60	32.8	21.1	Pass	
0.426	N	50	49.9	79	66	29	16.1	Pass	
1.704	N	35.8	34.9	73	60	37.2	25.1	Pass	



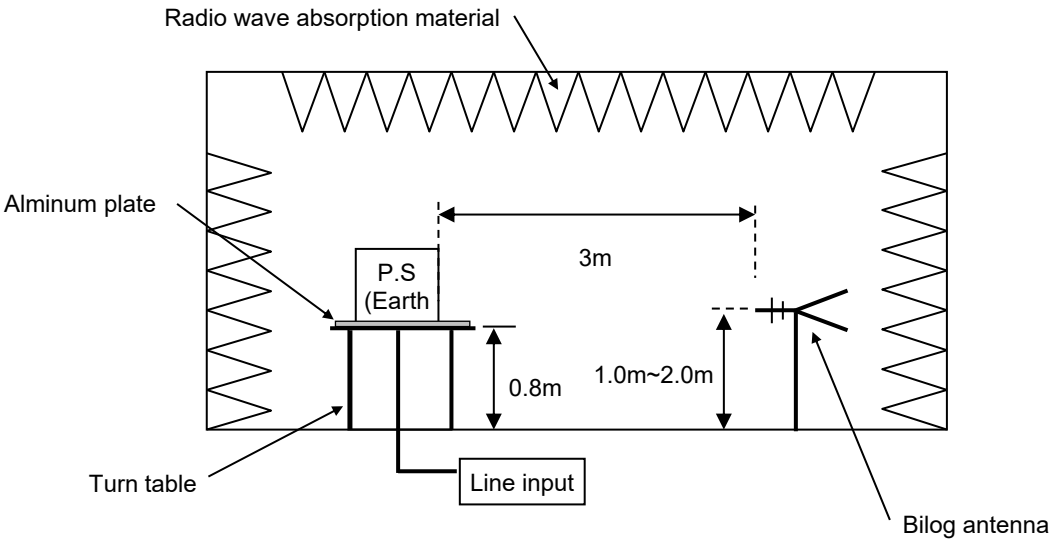
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
186.017	V	Stable	43	50	7	Pass	100	26.1	
54.478	V	Stable	32.6	50	17.4	Pass	100	301.9	
438.039	V	Stable	35	57	22	Pass	116.7	191.8	

DATA SHEET		Date	16-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name: MUW10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

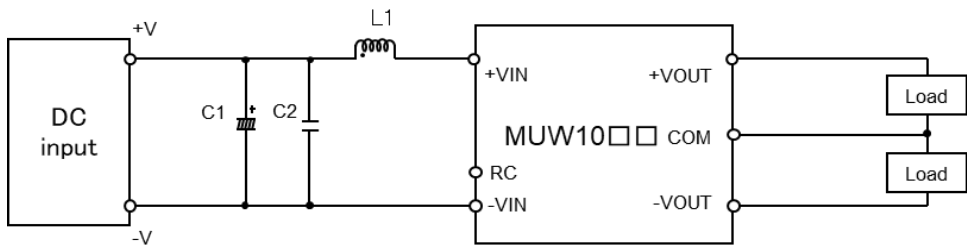


Fig.1 MUW10□□ Testing circuitry

C1 :	MUW1005□	25V 1500 μ F	Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MUW1012□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUW1024□	—	—
	MUW1048□	—	—
C2 :	MUW1005□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUW1012□	25V 10 μ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUW1024□	50V 4.7 μ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUW1048□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUW1005□	5000mA 2.2 μ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUW1012□	3500mA 4.7 μ H	Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING)
	MUW1024□	1600mA 22 μ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)
	MUW1048□	1100mA 47 μ H	Inductor(LQH5BPN470M38 MURATA MANUFACTURING)